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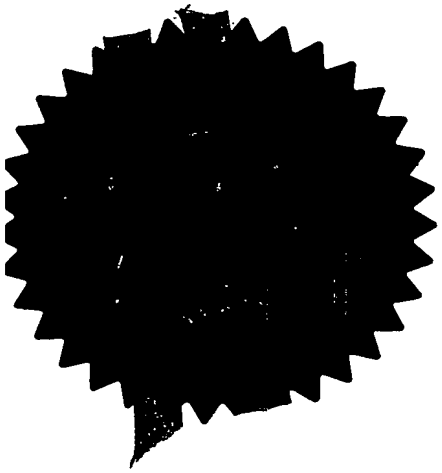

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1303 EAST ALGONQUIN ROAD,
SCHAUMBURG, ILLINOIS 60196,
U.S.A.

Patents ADP number *(if you know it)* ~~08281407004~~ 00615336004

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4. Title of the invention — METHOD AND DEVICE FOR REGULATING A VOLTAGE SUPPLY TO A SEMICONDUCTOR DEVICE

5. Name of your agent *(if you have one)*

"Address for service" in the United Kingdom to which all correspondence should be sent *(including the postcode)*

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HARRISON, CHRISTOPHER
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METHOD AND DEVICE FOR REGULATING A VOLTAGE SUPPLY TO A SEMICONDUCTOR DEVICE

The present invention relates to a method and device for regulating a voltage supply to a semiconductor device.

As the demand for portable electronic devices has increased so correspondingly has the requirement for increased battery life and processor performance.

While processor performance has continued to increase at a rapid rate, improvements in battery performance have not.

Additionally, in many cases the increase in processor performance has resulted in an increased power usage, which could result in many cases in a reduced battery life.

Consequently, there is a continuing drive to reduce power usage.

Once solution that manufactures have used to reduce power usage within portable electronic devices has included temporarily turning off unneeded peripherals; blocks of on-chip memory and, during idle periods, the processor itself.

Another solution involves lowering the supply voltage to an integrated circuit to the lowest voltage that is necessary to maintain the performance of the integrated circuit. This solution is based on the principle that the specified voltage supply requirements for an integrated circuit are based upon worst case conditions, for example worst case operational temperature and the quality of the

production process(i.e. manufactured process corner), whereas actual conditions are normally better than these.

One technique for determining the lowest voltage that would be needed to maintain the performance of an integrated circuit is to decrease the integrated circuit supply voltage in steps until the integrated circuit is measured to be operating just within a predetermined performance. However, the time taken to perform this operation can still result in a large waste of power.

It is desirable to improve this situation.

In accordance with a first aspect of the present invention there is provided a device for regulating a voltage supply to a semiconductor device according to claim 1.

This provides the advantage of allowing a minimum voltage supply to be determined quickly and without having to perform performance limit calculations.

In accordance with a second aspect of the present invention there is provided a method for regulating a voltage supply to a semiconductor device according to claim 8.

An embodiment of the invention will now be described, by way of example, with reference to the drawings, of which:

Figure 1 illustrates an arrangement for regulating a voltage supply to a semiconductor device according to an embodiment of the present invention;

Figure 2 illustrates a look-up table according to an embodiment of the present invention

Figure 3 illustrates a graphical representation of a look-up table according to an embodiment of the present invention.

Figure 1 shows an integrated circuit 100, a power management module 101 having a voltage supply regulator 112 for providing a supply voltage to the integrated circuit 100, a software module 102 for controlling the regulation of the supply voltage to the integrated circuit 100 and a memory module 103 having a look-up table 104 for storing performance data associated the integrated circuit 100.

The integrated circuit includes a reference counting circuit 106, a ring oscillator 107 that acts as a reference circuit, three comparators 108, 109, 110 and a look-up table register 111. It should be noted, however, that the comparators 108, 109, 110 and the look-up table register 111 could be located of chip from the integrated circuit 100.

The ring oscillator 107 (i.e. reference circuit) is arranged to generate a free running reference clock signal that is provided to the reference counting circuit 106. The reference circuit 107 is a subset of the circuits formed on the integrated circuit 100 and is used as a measure of the performance of the integrated circuit 100. The purpose of using the reference circuit 107 is to determine the performance of the integrated circuit 100 is to minimise the complexity of the device for regulating the voltage supply to the integrated circuit 100. However, it could also be possible to measure the operating performance of all of the circuits on the integrated circuit 100.

The frequency of the reference circuit 107 clock signal is related to how the reference circuit 107 is performing, and is dependent upon the operating conditions of the reference circuit 107, such as the operating temperature of the integrated circuit, the supply voltage supplied to the integrated circuit 100 and the manufactured process corner.

As stated above the reference circuit clock signal is a clock signal that is based upon the process corner case, the environmental conditions and the voltage of the integrated circuit 100. This is in contrast to the operating frequency of the integrated circuit 100, which is the clock rate to which the integrated circuit is working too.

The reference counting circuit 106 measures the clock signal, which as stated above is a reflection of the performance of the reference circuit 107, and provides the measurements to the comparators 108, 109, 110.

The comparators 108, 109, 110 are coupled to the look-up table register 111, with the look-up table register 111 also being coupled to the memory module 103 for accessing information stored in the look-up table 104 contained within the memory module 103.

As shown in figure 2 the look-up table 104, within the memory module 103, is preloaded with a set of reference circuit count values, where each set of reference circuit count values is associated with a respective supply voltage. Each set of reference circuit count values define a range of performance for the reference circuit 107, where, in this embodiment, the reference circuit count values differ for the different supply voltages, a graphical representation of the data is shown in figure 3.

Each set of reference circuit count values stored within the look-up table 104 defined three performance markers (i.e. three levels of performance of the integrated circuit). The first level 201, the upper performance limit, indicates the reference circuit count value that corresponds to the upper performance limit for the integrated circuit 100 at a specified voltage. The second level 202, the lower performance limit, indicates the reference circuit count value that corresponds to the lowest acceptable performance level for the integrated circuit 100 at a specified voltage. The third level 203, the critical lower performance level, indicates a reference circuit count value that corresponds to a level of performance at which logic operation failures within the integrated circuit 100 could occur for a specified voltage.

The values for the three performance levels 201, 202, 203 include a performance guard margin, which corresponds to an additional safety margin added to each of the determined performance levels for the reference circuit 105 to account for possible differences between the performance of the reference circuit 107 and the integrated circuit 100 as a whole. If the performance of the integrated circuit 100 as a whole was being measured, rather than just the reference circuit 107, it would be unnecessary to include a guard margin/safety margin within the performance level values.

By way of illustration, figure 2 shows that for the current embodiment nine supply voltages 204 for the integrated circuit 100 have been defined where each supply voltage is associated with a respective performance range (i.e. a range of reference circuit count values), where the performance range for the first voltage of 1.2 provides a reference circuit count value for the upper performance limit of 290 counts, a reference circuit count value for the lower performance limit of 275 counts and a reference circuit count value for the critical lower performance level of 264 counts.

The performance limits stored in the look-up table 104 are based on two main parameters: IR (i.e. current resistance) drop value (voltage reduction due to current flow through metal interconnects) and the accuracy of the voltage supply regulator 112.

The critical lower performance level 203 is set by the minimal required voltage level and IR drop value, where IR drop value depends on existing absolute supply voltage level. The critical lower performance level 203 is set such that if the maximum IR drop occurs the supply voltage inside the integrated circuit 100 would be so low that the most constrained delay paths might begin to malfunction.

The lower performance limit 202 is higher than the critical lower performance level 203 by a value proportional to the voltage raise of one minimum step of the voltage supply regulator 112 plus some spare margin.

The higher performance limit 201 is higher than the lower performance limit 202 by a value proportional to a voltage raise of one and the half voltage steps of the voltage supply regulator 112 plus some spare margin.

The software module 102, which receives information from the power management module 101 as to the voltage supply being provided to the integrated circuit 100, is arranged to load the three reference circuit count performance values associated with the supplied voltage into the look-up table register 111.

The look-up table register 111 is arranged to provide the upper performance level value and the lower performance level reference circuit count value to the first comparator 108 and second comparator 109 respectively and the critical lower performance level reference circuit count value to the third comparator 110.

The first comparator 108 compares the measured reference count value received from the reference counting circuit 106 with the reference circuit count value received from the look-up table register 111 (i.e. the upper performance level reference circuit count value).

If the measured reference count value falls below the upper performance level reference circuit count value the first comparator 108 provides no output.

If the measured reference count value is above the upper performance level reference circuit count value (i.e. the supply voltage is unnecessarily high) the first comparator 108 issues an interrupt request to the software module 102 requesting a voltage decrease. On receipt of the interrupt request the software module 102 initiates an instruction to the power management module 101 to lower the voltage supply to the integrated circuit 100 to the next lower voltage supply level within the look-up table and the software module 102 initiates the loading of the three reference circuit count performance values associated with the new supplied voltage into the look-up table register 111.

The second comparator 109 compares the measured reference circuit count value received from the reference counting circuit 106 with the reference circuit count value received from the look-up table register 111 (i.e. the lower performance level reference circuit count value).

If the measured reference count value is higher than the lower performance level reference circuit count value the second comparator 109 provides no output.

If the measured reference count value is below the lower performance level reference circuit count value (i.e. the supply voltage is too low) the second comparator 109 issues an interrupt request to the software module 102 requesting a voltage increase. On receipt of the interrupt request the software module 102

initiates an instruction to the power management module 101 to increase the voltage supply to the integrated circuit 100 to the next highest voltage supply level within the look-up table and the software module 102 initiates the loading of the three reference circuit count performance values associated with the new supplied voltage into the look-up table register 111.

The third comparator 110 compares the measured reference circuit count value received from the reference counting circuit 106 with the reference circuit count value received from the look-up table register 111 (i.e. the critical lower performance reference circuit count value).

If the measured reference circuit count value falls below the critical lower performance level reference circuit count value, which is placed at a lower count level to the lower performance level, this could indicate that a previous request to increase the voltage supply to the integrated circuit 100 is occurring too slowly and/or the operating environment conditions are degrading at a fast rate. In response to the measured reference circuit count value falling below the critical lower performance level the third comparator 110 issues a high priority interrupt request to the software module 102 requesting a voltage increase. On receipt of the high priority interrupt request the software module places a high priority instruction to the power management module 101 requesting an increase in the voltage supply to the integrated circuit 100 to the next higher voltage supply level and, if not already performed as a result of any previous voltage request interrupts from the second comparator 109, the software module 102 initiates the loading of the three reference circuit count performance values associated with the new supply voltage to the look-up table register 111.

It will be apparent to those skilled in the art that the disclosed subject matter may be modified in numerous ways and may assume many embodiments other than the preferred forms specifically set out as described above, for example the above embodiments could be arranged such that the look-up table 104 could have

more or less than three performance levels and the change in voltage could be to voltage levels other than the next value up or down from the current voltage value within the look-up table 104, rather than the comparators 108, 109, 110 being arranged to send a signal when a performance level has been reached the comparators 108, 109, 110 could be arranged to stop sending a signal when a performance level has be reached.

CLAIMS

1. A device for regulating a voltage supply to a semiconductor device, the device comprising memory for storing a plurality of performance ranges, wherein the respective performance ranges are associated with a respective supply voltage; means for measuring the performance of the semiconductor device; and a regulator for modifying the supply voltage to the semiconductor device if the measured performance of the semiconductor device is not within a predetermined portion of the performance range associated with the voltage supplied to the semiconductor device.

2. A device according to claim 1, wherein the performance range is defined to have an upper performance limit such that if the measured performance of the semiconductor device is above the upper performance limit the regulator is arranged to reduce the voltage supplied to the semiconductor device.

3. A device according to claim 1 or 2, wherein the performance range is defined to have a lower performance limit such that if the measured performance of the semiconductor device is below the lower performance limit the regulator is arranged to increase the voltage supplied to the semiconductor device.

4. A device according to any of claim 1 to 3, wherein the performance range is defined to have a critical lower performance limit such that if the measured performance of the semiconductor device is below the critical lower

performance limit the regulator is arranged to increase the voltage supplied to the semiconductor device.

5. A device according to any of claims 1 to 4, wherein the means for measuring the performance is arranged to measure the performance of the semiconductor device by measuring the performance of a reference circuit that forms part of the semiconductor device.

6. A device according to claim 5, wherein the plurality of performance ranges are arrange to include a performance guard margin to compensate for differences between the measured performance of the reference circuit and the actual performance of the complete integrated circuit.

7. A device according to any preceding claim, further comprising a ring oscillator, wherein the means for measuring the performance measures the frequency of the ring oscillator for providing a measure of the performance of the integrated circuit.

8. A method for regulating a voltage supply to a semiconductor device, the method comprising storing a plurality of performance ranges, wherein the respective performance ranges are associated with a respective supply voltage; measuring the performance of the semiconductor device; and modifying the supply voltage to the semiconductor device if the measured performance of the semiconductor device is not within a predetermined portion of the performance range associated with the voltage supplied to the semiconductor device.

9. A device substantially as herein described with reference to the accompanying figures.

10. A method substantially as herein described with reference to the accompanying figures.

ABSTRACT

METHOD AND DEVICE FOR REGULATING A VOLTAGE SUPPLY TO A SEMICONDUCTOR DEVICE

A device for regulating a voltage supply to a semiconductor device, the device comprising memory for storing a plurality of performance ranges, wherein the respective performance ranges are associated with a respective supply voltage; means for measuring the performance of the semiconductor device; and a regulator for modifying the supply voltage to the semiconductor device if the measured performance of the semiconductor device is not within a predetermined portion of the performance range associated with the voltage supplied to the semiconductor device.

(Figure 1)

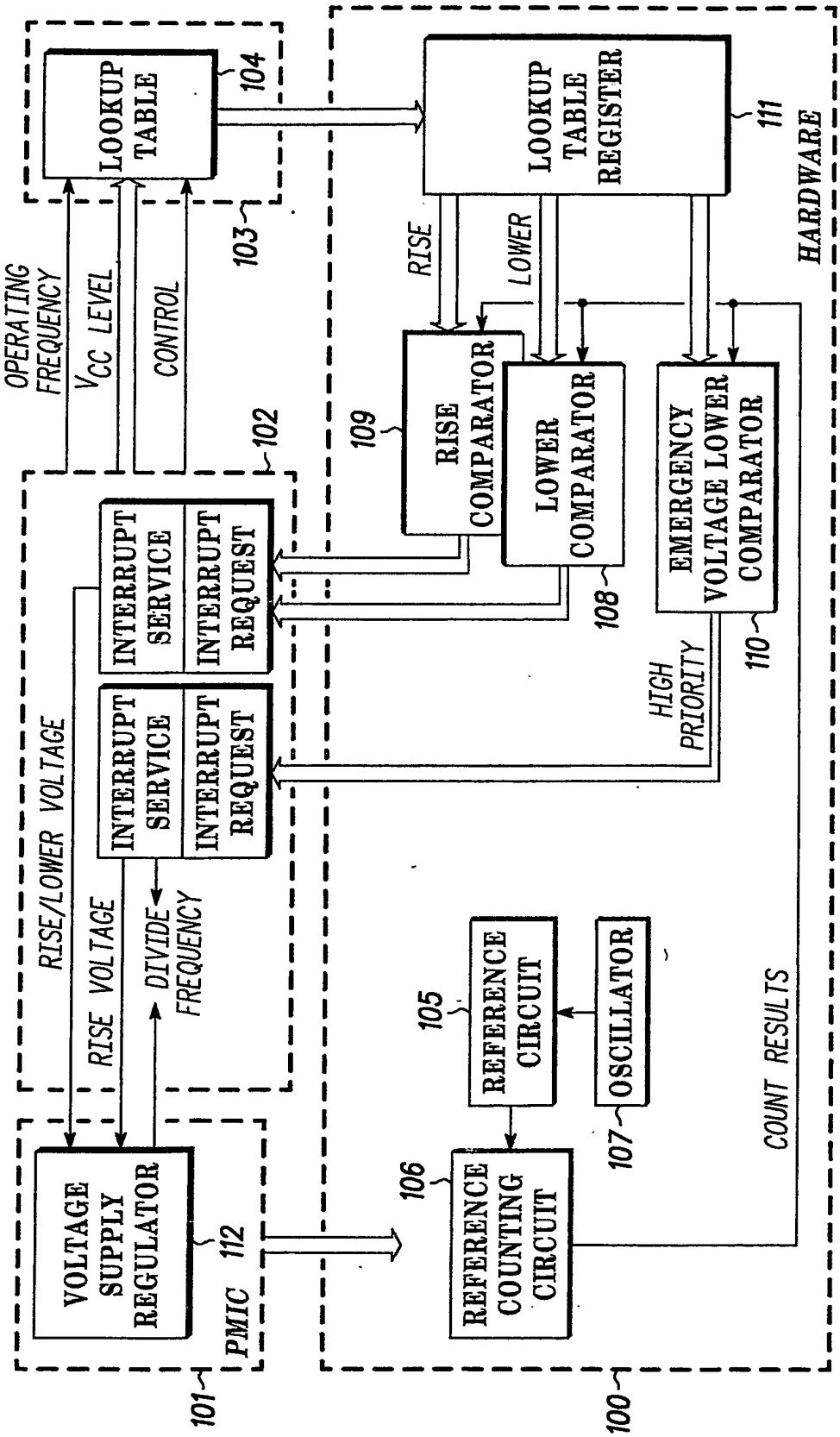
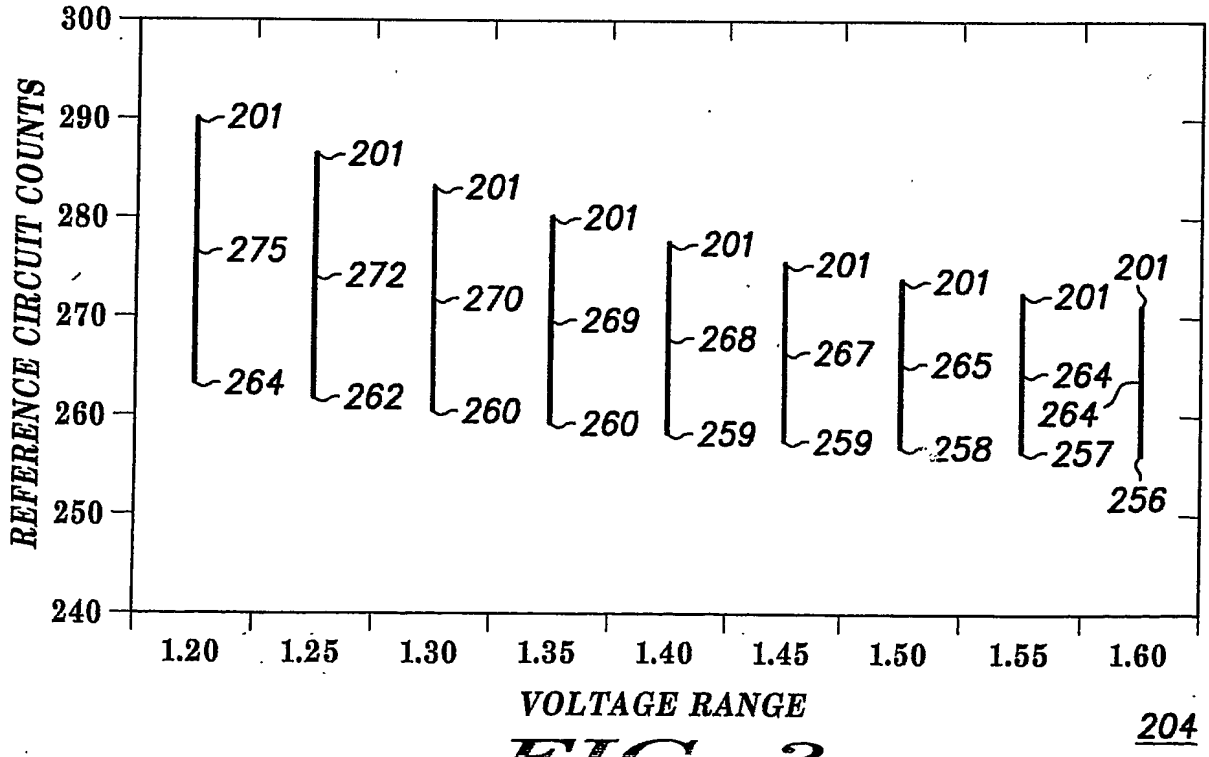

LOOKUP TABLE
104
LOOKUP TABLE REGISTER
111
HARDWARE
OPERATING FREQUENCY
V_{CC} LEVEL
CONTROL
103
RISE
LOWER
102
109
RISE COMPARATOR
LOWER COMPARATOR
EMERGENCY VOLTAGE LOWER COMPARATOR
108
110
INTERRUPT SERVICE
INTERRUPT REQUEST
INTERRUPT SERVICE
INTERRUPT REQUEST
HIGH PRIORITY
RISE/LOWER VOLTAGE
RISE VOLTAGE
DIVIDE FREQUENCY
105
REFERENCE CIRCUIT
OSCILLATOR
107
106
REFERENCE COUNTING CIRCUIT
COUNT RESULTS
VOLTAGE SUPPLY REGULATOR
112
PMIC
101
100

FIG. 1

204 VOLTAGE	203 FREQUENCY DIVISION PLUS RISE VOLTAGE	202 RISE VOLTAGE	201 LOWER VOLTAGE
1.20	263	276	291
1.26	262	273	287
1.30	261	271	283
1.35	260	269	280
1.40	259	267	277
1.45	258	266	275
1.50	258	265	273
1.55	257	264	272
1.60	257	264	271

104

FIG. 2



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